

Abstract of the Disclosure

A test device for testing integrated circuits includes a lid and a base joined at a hinge and secured 5 together with a latch. Within the base is some form of socket body that electrically connects the integrated circuit under test to the item the socket is mounted to (i.e. load board). Attached to the lid are bearing assemblies. An incline cam that may or may not include 10 arresting points along the incline, rotates on the bearings which are attached to the lid. A handle is attached to the cam. A pressure plate is attached to the cam. The cam, which is attached to the handle, provides 15 a rotating means for lowering a pressure plate. The means for lowering a pressure plate may allow incremental lowering of a pressure plate by means of the stop points on the cam. The base may include a sight groove for examination of the integrated circuit and internal socket parts.